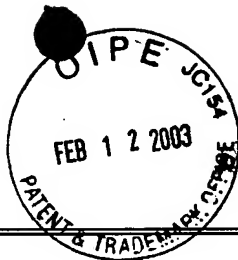


Docket No.: 87280.1762
Customer No.: 30734



RECEIVED
FEB 19 2003
TECHNOLOGY CENTER R3700

PATENT

LIST OF ART CITED BY APPLICANT

(PTO-1449)

ATTY. DOCKET NO.
87280.1762

SERIAL NO.
10/021,048

APPLICANT
Ohler L. Kinney, Jr., et al.

FILING DATE
12/19/01

GROUP
3749-1724

RECEIVED

FEB 24 2003

TC 1700

U.S. PATENT DOCUMENTS

	EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
A	CP	3,875,269	04/01/75	Forchini, et al.	261	111	01/18/73
B		4,416,836	11/22/83	Sinek	261	112	12/03/81
C		4,422,983	12/27/83	Bardo, et al.	261	24	06/16/82
D		6,250,610	06/26/01	Flaherty, et al.	261	109	08/23/99
E		5,487,849	01/30/96	Curtis	261	30	12/03/93
F	CP	5,569,415	10/29/96	Phelps	261	23.1	09/18/95
G							
H							
I							
J							
K							
L							
M							
N							
O							
P							
Q							
R							
S							
T							

FOREIGN PATENT DOCUMENTS

	EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation
U							
V							
W							
X							
Y							
Z							
AA							
BB							
CC							
DD							
EE							
FF							
GG							

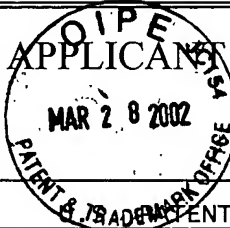
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

HH	CP	International Search Report dated January 14, 2003
II	CP	International Search Report dated January 14, 2003
JJ		
KK		
LL		
MM		
NN		

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

LIST OF ART CITED BY APPLICANT (PTO-1449)						ATTY. DOCKET NO. 87280.1762		SERIAL NO. 10/021,048	
				APPLICANT Ohler L. Kinney, Jr., et al.					
				FILING DATE December 19, 2001		GROUP 3749 1724			

DOMESTIC PATENT DOCUMENTS							
	EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
A	CB	4,514,202	04/30/85	Kinney, Jr. et al.	55	440	09/12/84
B							
C							
D							
E							
F							
G							
H							
I							
J							
K							
L							
M							
N							
O							
P							
Q							
R							
S							
T							

FOREIGN PATENT DOCUMENTS							
	EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation
U							
V							
W							
X							
Y							
Z							
AA							
BB							
CC							
DD							
EE							
FF							
GG							

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)	
HH	
II	
JJ	
KK	
LL	
MM	
NN	

EXAMINER <i>OS. BL</i>	DATE CONSIDERED <i>8-28-03</i>
------------------------	--------------------------------

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

RECEIVED

APR 02 2002

TECHNOLOGY CENTER R3700